

## Abstract

The invention relates to a method and a device for testing the detectability of at least one flaw in a component, or for evaluating ultrasonic signals of the flaw. The method provides for an electronic specification of the flaw to be generated, which includes a two-dimensional or three-dimensional point pattern. This specification predefines the number, position, shape, orientation, and dimensions of flaws to be deliberately generated. A test specimen is produced, where for each point of the point pattern, a microcrack is generated at the position of this point. An ultrasonic image of the test specimen is recorded and evaluated. The test specimen is preferably made out of a material transparent to visible light, e.g. crown glass, borosilicate glass, or quartz glass. The microcracks are preferably produced, using internal laser engraving.